



PHOTODIODE TEST SYSTEM

SEMICONDUCTOR TEST SERVICES

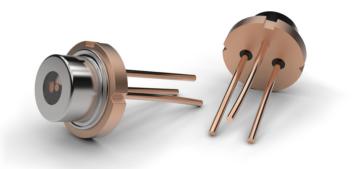


Custom-built Laser Diode Test System

Electron Test Equipment is a manufacturer of high performance Laser Diode Test Systems that provide accelerated aging, burn-in, and qualification testing for laser diodes. The system is a modular design, allowing the operator to test between 64 to 1024 laser diodes.

TEST VARIOUS LASER DIODE PACKAGES

The system has the flexibility to test various laser packages such as TO-Can, CoC, & Butterfly (with or without pigtail connectors) - all from one system. Simply swap the interface board and you are ready to test.



HUMIDITY & TEMPERATURE CYCLING

In addition to the standard burn-in and reliability test modes, the test components can be placed in environmental chambers to provide additional compliance testing for humidity and thermal cycling.

OPTICAL SPECTRUM ANALYSIS

The Laser Diode Test System is designed to interface with an Optical Spectrum Analyser to measure detailed laser parameters of each laser diode.

SPECIFICATION OVERVIEW

- Test Modes: ACC / APC / LIV
- Number of devices: 64 to 1024
- Temperature Control: 25 to 105°C
- Temperature Accuracy: ±2°C
- Operating Current Stability: 0.1% Full Scale
- Operating Currents: 200mA / 500mA / Custom High Current
- LIV Curve, Threshold Current, Operating Current, Forward Voltage, Monitoring Current and Data Collection

Custom-built Photodiode Test System

Electron Test Equipment is a manufacturer of high performance Photodiode Test Systems that provide accelerated aging, burn-in, and qualification testing for photodiodes. The system is a modular design, allowing the operator to test between 64 to 1024 photodiodes.



ENSURE PHOTODIODE RELIABILITY

With autonomous vehicles and drones relying heavily on laser and photodiodes for accuracy, our Photodiode Test System can perform Accelerated Life Testing to ensure reliability in the field.

HUMIDITY & TEMPERATURE CYCLING

In addition to the standard burn-in (175° C) and reliability test modes, the test components can be placed in environmental chambers to provide additional compliance testing for humidity and thermal cycling.

USER INTERFACE & REPORTING

The software interface has an easy to use dashboard that allows for quick configuration and detailed performance analysis of each photodiode. Interactive reports and charts are dynamically updated and can be viewed securely online.

SPECIFICATION OVERVIEW

- Current Range: 200nA 32,000nA
- Temperature Control: 25 to 200°C
- Temperature Accuracy: ± 2°C
- Operating Current Stability: 0.1% Full Scale
- Number of Devices: 64 to 1024
- Voltage Range: 0 40 VDC
- Calculations: FIT (Failure in Time) & Mean Time to Failure (MTTF)
- Measured values: Dark Current, I-V, Voc, Isc, Vmax, Imax, Imin

Testing Services

No matter what industry you are in, it is crucial to have detailed knowledge about the reliability and operating limits of your component or electronic assembly.



HALT SERVICES

Highly Accelerated Life Testing (HALT) is a proven method of shortening the time-to-market period and providing critical data about your product's reliability.

HAST SERVICES

Highly Accelerated Temperature/Humidity Stress Test (HAST) loads the device with heat & humidity and reveals concealed defects that could cause premature failure.

View Real-time Test Data

You don't want to wait weeks to view the data or wait for the end of the test cycle. We provide you secured remote access during testing with the flexibility to:



View dashboard test data in real-time



Receive alerts & notifications



Analyse reports and charts dynamically



Get In Touch



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